

**N-Channel Enhancement Mode Power MOSFET**

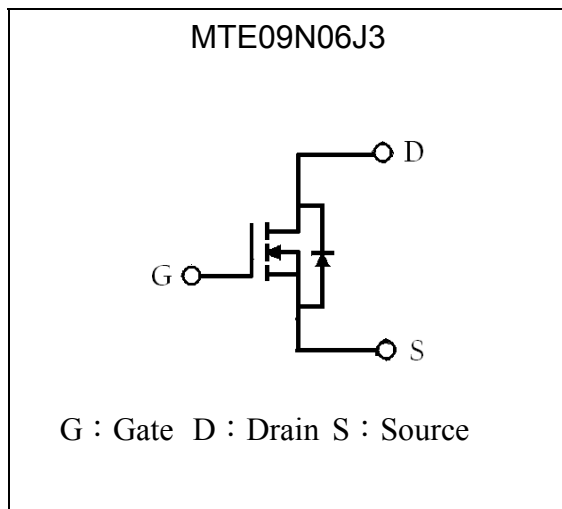
# MTE09N06J3

<b>BV<sub>DSS</sub></b>	<b>60V</b>
<b>I<sub>D</sub>@V<sub>GS</sub>=10V, T<sub>C</sub>=25°C</b>	<b>50A</b>
<b>R<sub>DS(ON)</sub>@V<sub>GS</sub>=10V, I<sub>D</sub>=20A</b>	<b>7 mΩ (typ)</b>
<b>R<sub>DS(ON)</sub>@V<sub>GS</sub>=7V, I<sub>D</sub>=20A</b>	<b>7.9 mΩ (typ)</b>

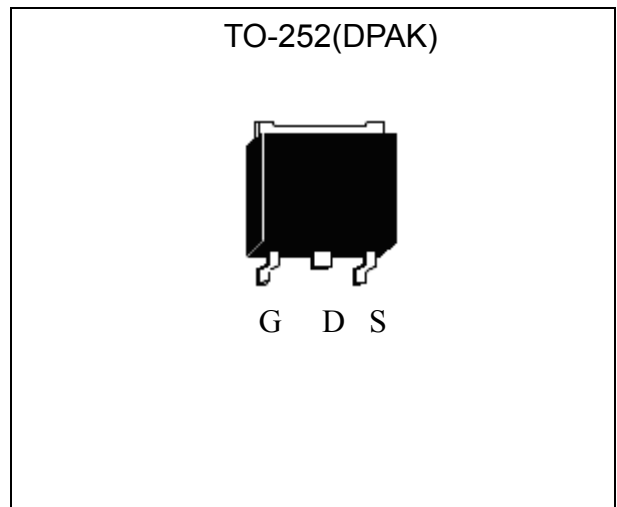
**Features**

- Low On Resistance
- Simple Drive Requirement
- Low Gate Charge
- Fast Switching Characteristic
- Pb-free lead plating and halogen-free package

**Symbol**

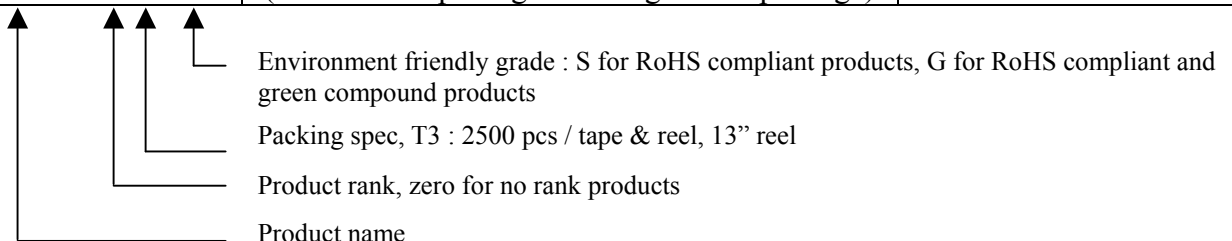


**Outline**



**Ordering Information**

Device	Package	Shipping
MTE09N06J3-0-T3-G	TO-252 (Pb-free lead plating and halogen-free package)	2500 pcs / tape& reel



**Absolute Maximum Ratings** ( $T_C=25^{\circ}\text{C}$ )

Parameter	Symbol	Limits	Unit	
Drain-Source Voltage (Note 1)	$V_{DS}$	60	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$		
Continuous Drain Current @ $T_C=25^{\circ}\text{C}$ , $V_{GS}=10\text{V}$ (silicon limit) (Note 1)	$I_D$	70	A	
Continuous Drain Current @ $T_C=100^{\circ}\text{C}$ , $V_{GS}=10\text{V}$ (silicon limit) (Note 1)		50		
Continuous Drain Current @ $T_C=25^{\circ}\text{C}$ , $V_{GS}=10\text{V}$ (package limit) (Note 1)		50		
Continuous Drain Current @ $T_A=25^{\circ}\text{C}$ , $V_{GS}=10\text{V}$ (Note 2)	$I_{DSM}$	13		
Continuous Drain Current @ $T_A=70^{\circ}\text{C}$ , $V_{GS}=10\text{V}$ (Note 2)		10		
Pulsed Drain Current @ $V_{GS}=10\text{V}$ (Note 3)	$I_{DM}$	180		
Avalanche Current (Note 3)	$I_{AS}$	45		
Single Pulse Avalanche Energy @ $L=0.1\text{mH}$ , $I_D=45\text{A}$ , $V_{DD}=25\text{V}$ (Note 2)	$E_{AS}$	101	mJ	
Repetitive Avalanche Energy (Note 3)	$E_{AR}$	10		
Power Dissipation	$P_D$	$T_C=25^{\circ}\text{C}$ (Note 1)	75	W
		$T_C=100^{\circ}\text{C}$ (Note 1)	37.5	
	$P_{DSM}$	$T_A=25^{\circ}\text{C}$ (Note 2)	2.5	
		$T_A=70^{\circ}\text{C}$ (Note 2)	1.6	
Operating Junction and Storage Temperature	$T_j, T_{stg}$	-55~+175	$^{\circ}\text{C}$	

**Thermal Data**

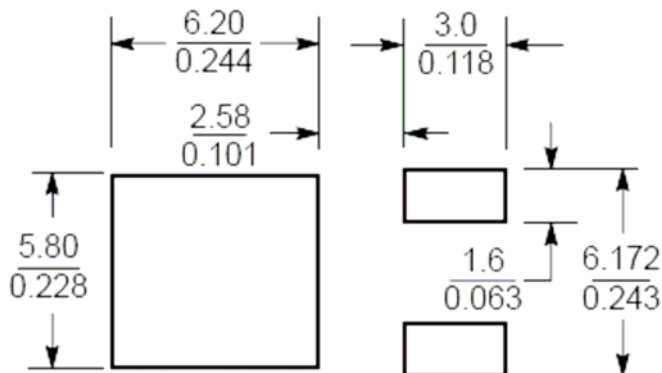
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-case, max	$R_{\theta JC}$	2	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-ambient, max (Note 2)	$R_{\theta JA}$	50	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-ambient, max (Note 4)	$R_{\theta JA}$	110	$^{\circ}\text{C}/\text{W}$

- Note : 1. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=175^{\circ}\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
2. The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2 oz. copper, in a still air environment with  $T_A=25^{\circ}\text{C}$ . The power dissipation  $P_{DSM}$  is based on  $R_{\theta JA}$  and the maximum allowed junction temperature of  $150^{\circ}\text{C}$ . The value in any given application depends on the user's specific board design.
3. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=175^{\circ}\text{C}$ . Ratings are based on low frequency and low duty cycles to keep initial  $T_J=25^{\circ}\text{C}$ .
4. When mounted on the minimum pad size recommended (PCB mount),  $t \leq 10\text{s}$ .

**Characteristics (T<sub>j</sub>=25°C, unless otherwise specified)**

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>					
BV <sub>DSS</sub>	60	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔBV <sub>DSS</sub> /ΔT <sub>j</sub>	-	0.06	-	V/°C	Reference to 25°C, I <sub>D</sub> =250μA
V <sub>GS(th)</sub>	2.0	-	4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA
*G <sub>FS</sub>	-	29	-	S	V <sub>DS</sub> = 5V, I <sub>D</sub> =20A
I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> =±20V
I <sub>DSS</sub>	-	-	1	μA	V <sub>DS</sub> = 60V, V <sub>GS</sub> = 0V
	-	-	10		V <sub>DS</sub> = 48V, V <sub>GS</sub> = 0V, T <sub>j</sub> =125°C
*R <sub>DS(ON)</sub>	-	7	8.8	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> =20A
	-	7.9	13.5		V <sub>GS</sub> = 7V, I <sub>D</sub> =20A
<b>Dynamic</b>					
*Q <sub>g</sub>	-	32	-	nC	V <sub>DD</sub> =30V, I <sub>D</sub> =20A, V <sub>GS</sub> =10V
*Q <sub>gs</sub>	-	7.5	-		
*Q <sub>gd</sub>	-	9.7	-		
*t <sub>d(ON)</sub>	-	16	-	ns	V <sub>DD</sub> =30V, I <sub>D</sub> =20A, V <sub>GS</sub> =10V, R <sub>G</sub> =3Ω
*t <sub>r</sub>	-	22.8	-		
*t <sub>d(OFF)</sub>	-	39.4	-		
*t <sub>f</sub>	-	15	-		
C <sub>iss</sub>	-	1500	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V, f=1MHz
C <sub>oss</sub>	-	272	-		
C <sub>rss</sub>	-	140	-		
R <sub>g</sub>	-	2.2	-		
<b>Source-Drain Diode</b>					
*I <sub>S</sub>	-	-	50	A	
*V <sub>SD</sub>	-	0.69	1	V	I <sub>S</sub> =1A, V <sub>GS</sub> =0V
*t <sub>rr</sub>	-	21	-	ns	V <sub>GS</sub> =0V, I <sub>F</sub> =20A, dI <sub>F</sub> /dt=100A/μs
*Q <sub>rr</sub>	-	18.5	-	nC	

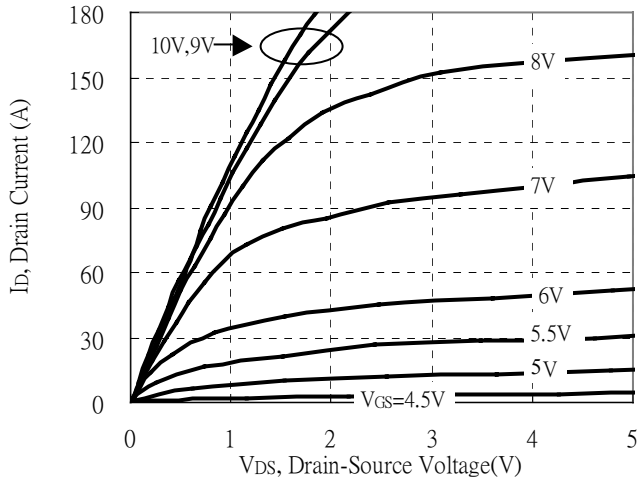
\*Pulse Test : Pulse Width ≤300μs, Duty Cycles ≤2%

**Recommended soldering footprint**

 Unit (  $\frac{\text{mm}}{\text{inch}}$  )

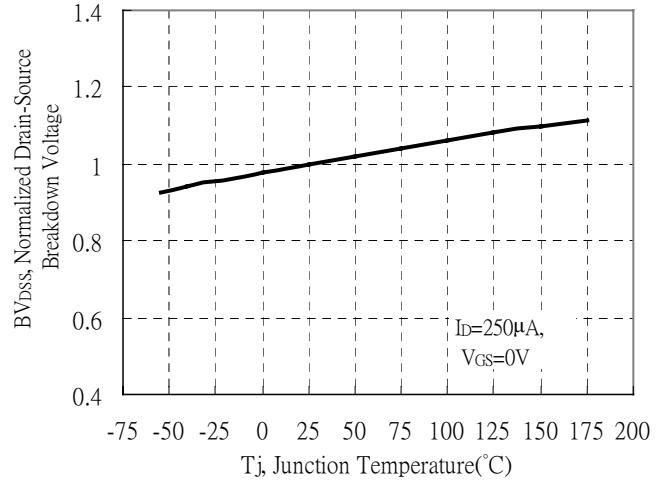


### Typical Characteristics

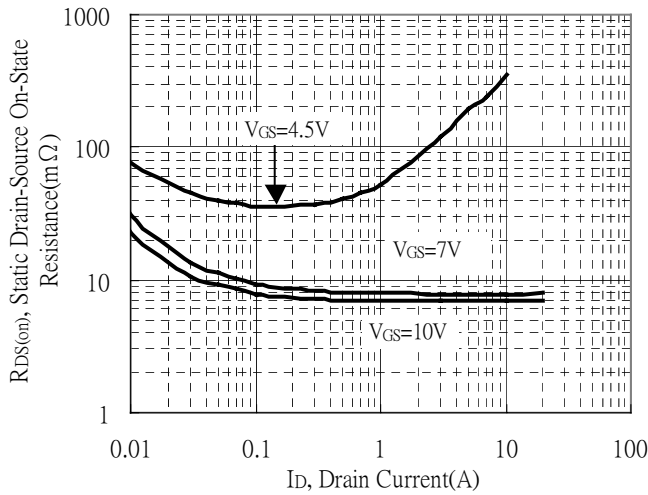
Typical Output Characteristics



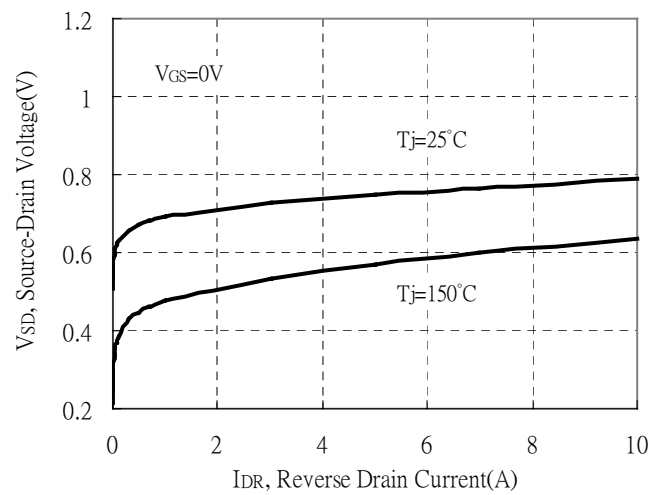
Brekdown Voltage vs Ambient Temperature



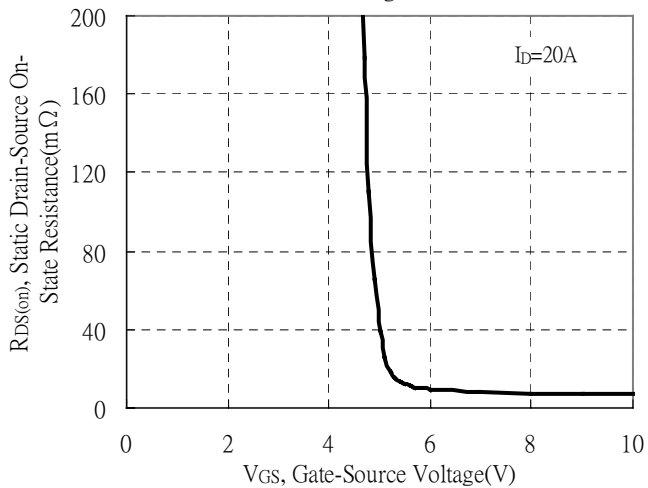
Static Drain-Source On-State resistance vs Drain Current



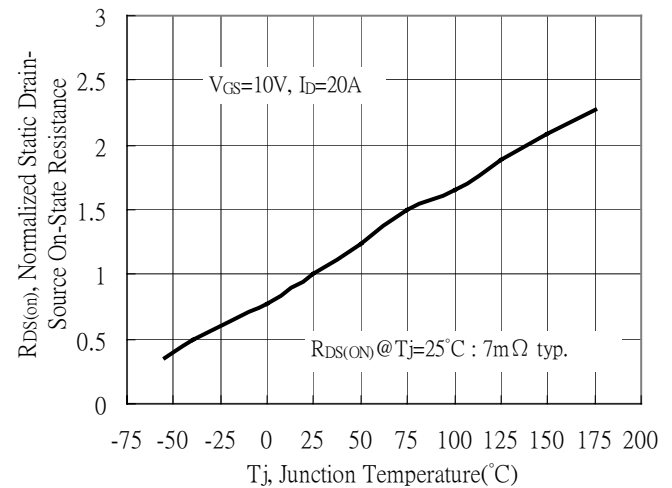
Reverse Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage

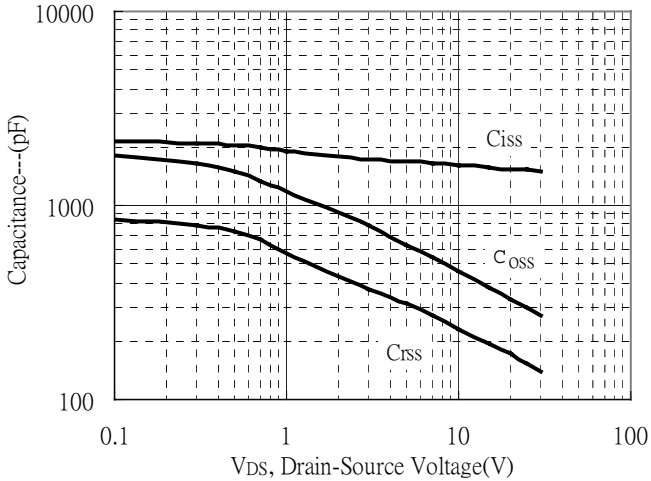


Drain-Source On-State Resistance vs Junction Temperature

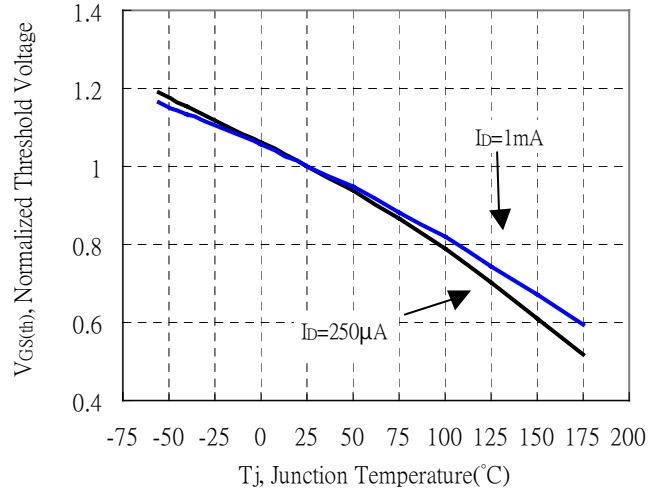


**Typical Characteristics(Cont.)**

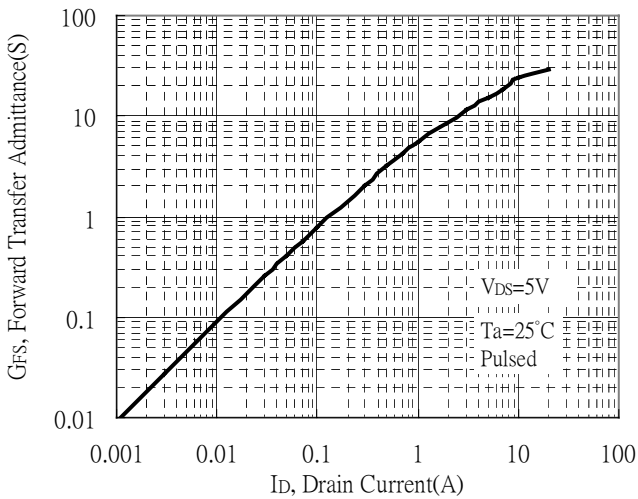
Capacitance vs Drain-to-Source Voltage



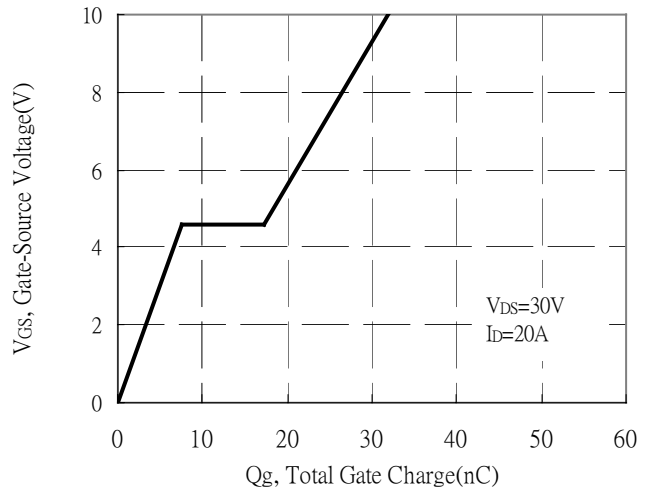
Threshold Voltage vs Junction Temperature



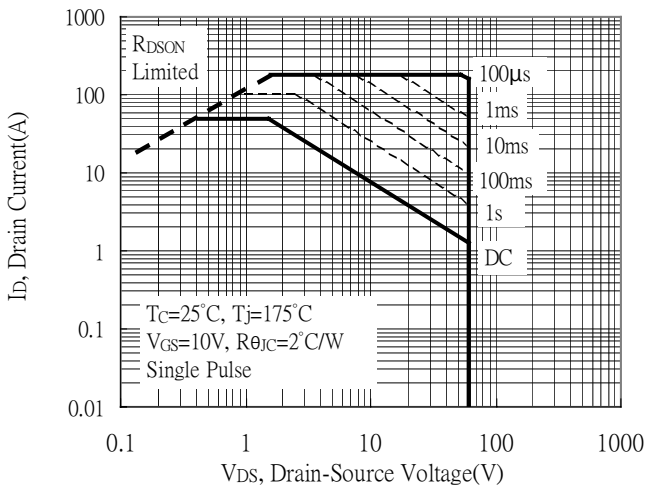
Forward Transfer Admittance vs Drain Current



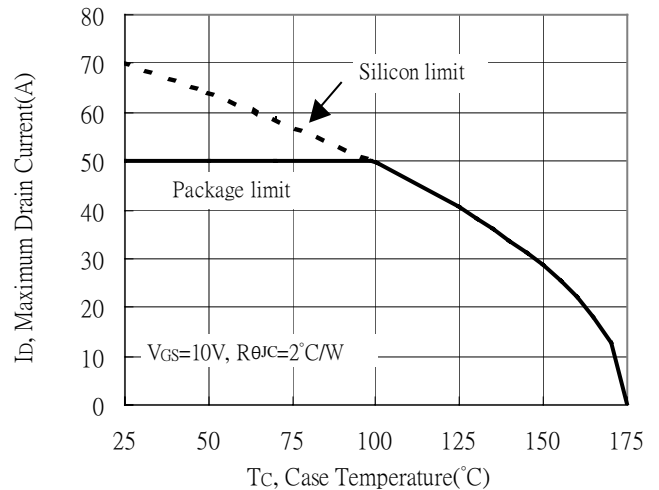
Gate Charge Characteristics



Maximum Safe Operating Area

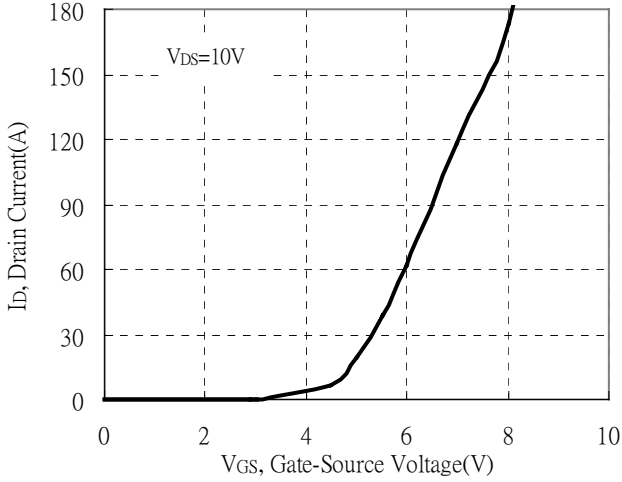


Maximum Drain Current vs Case Temperature

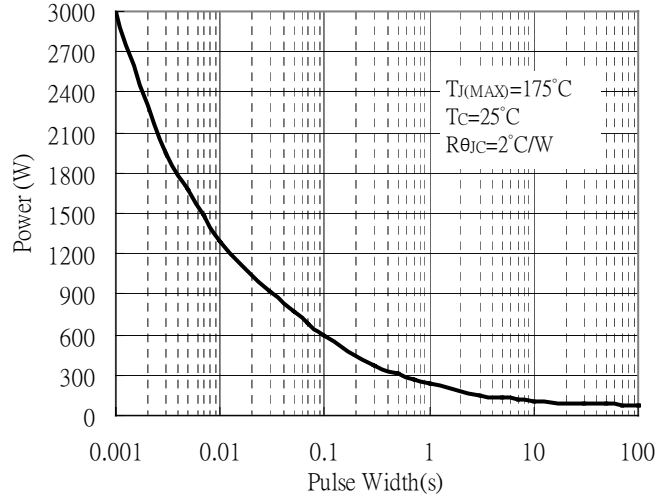


**Typical Characteristics(Cont.)**

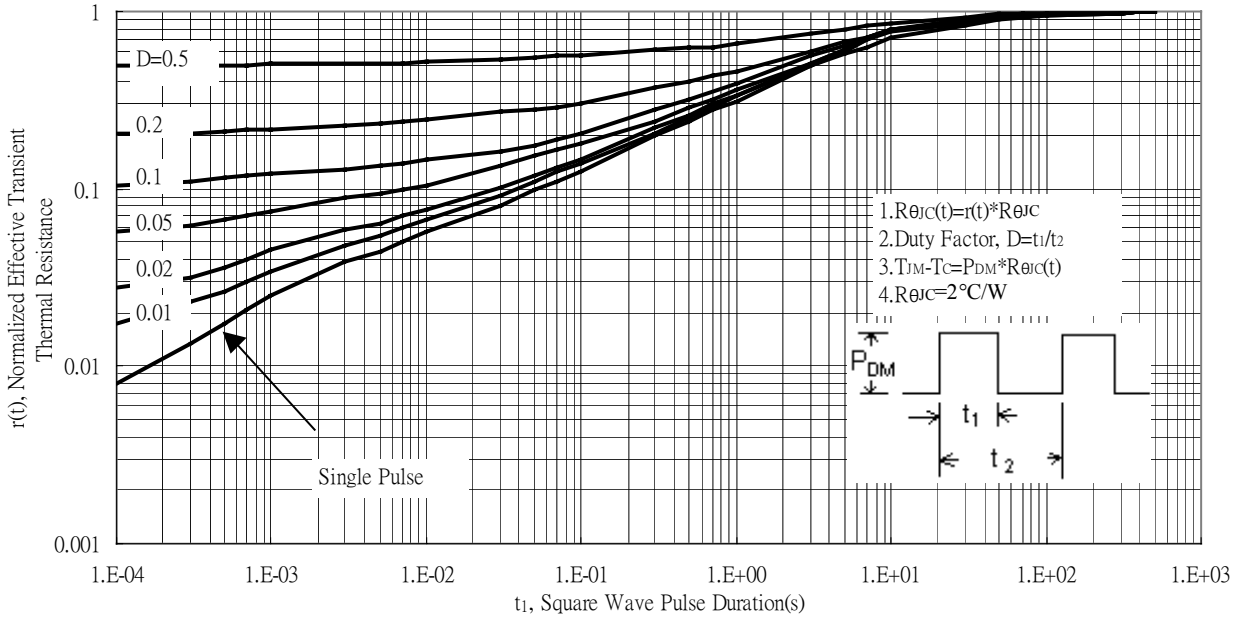
Typical Transfer Characteristics



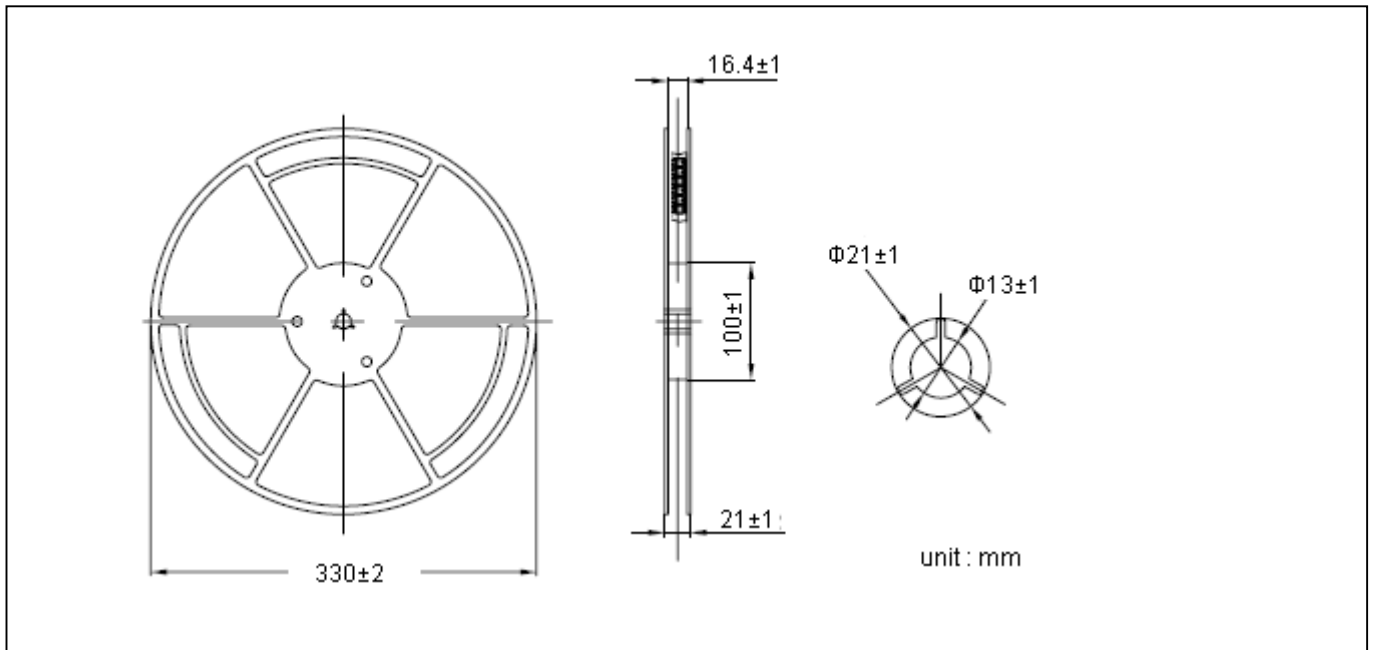
Single Pulse Power Rating, Junction to Case



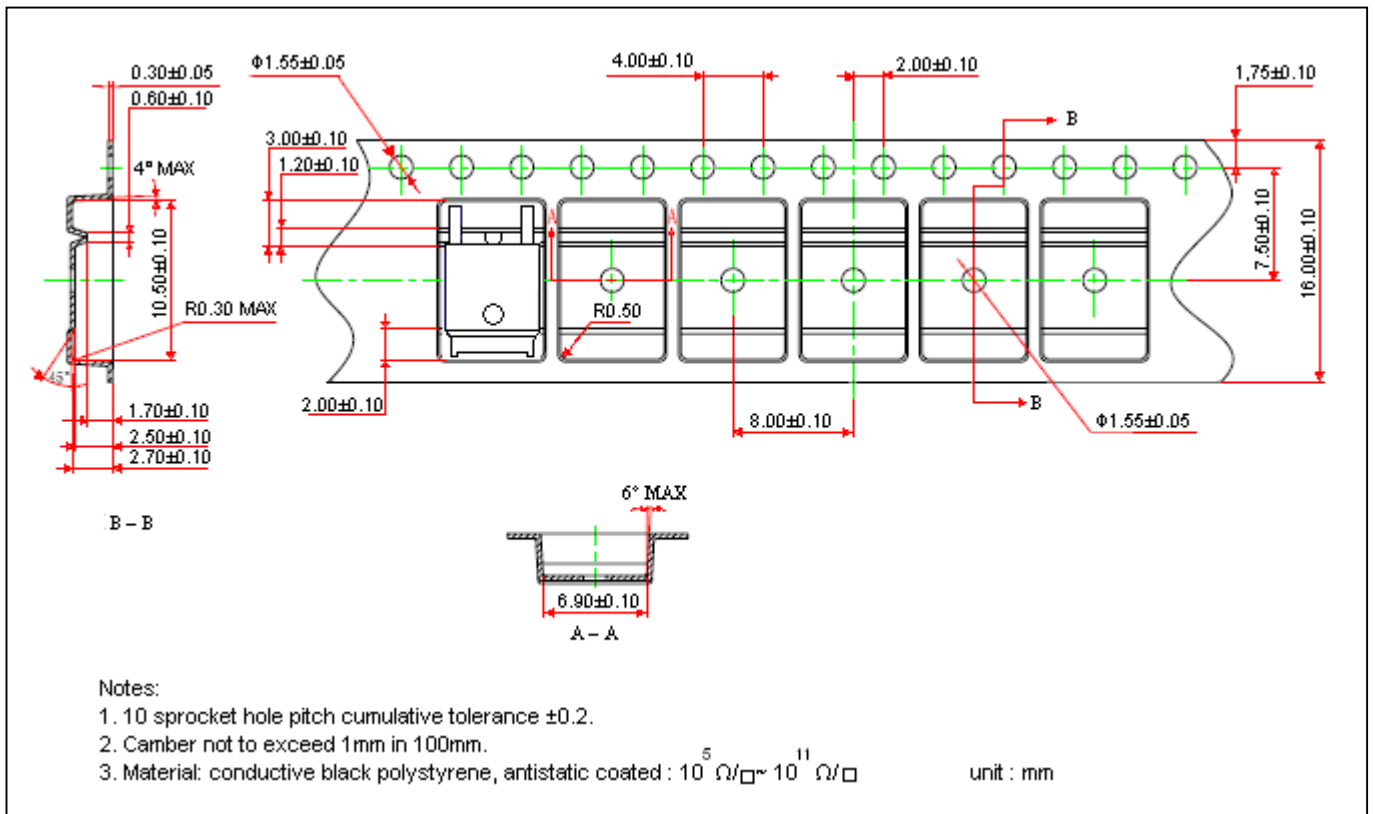
Transient Thermal Response Curves



**Reel Dimension**



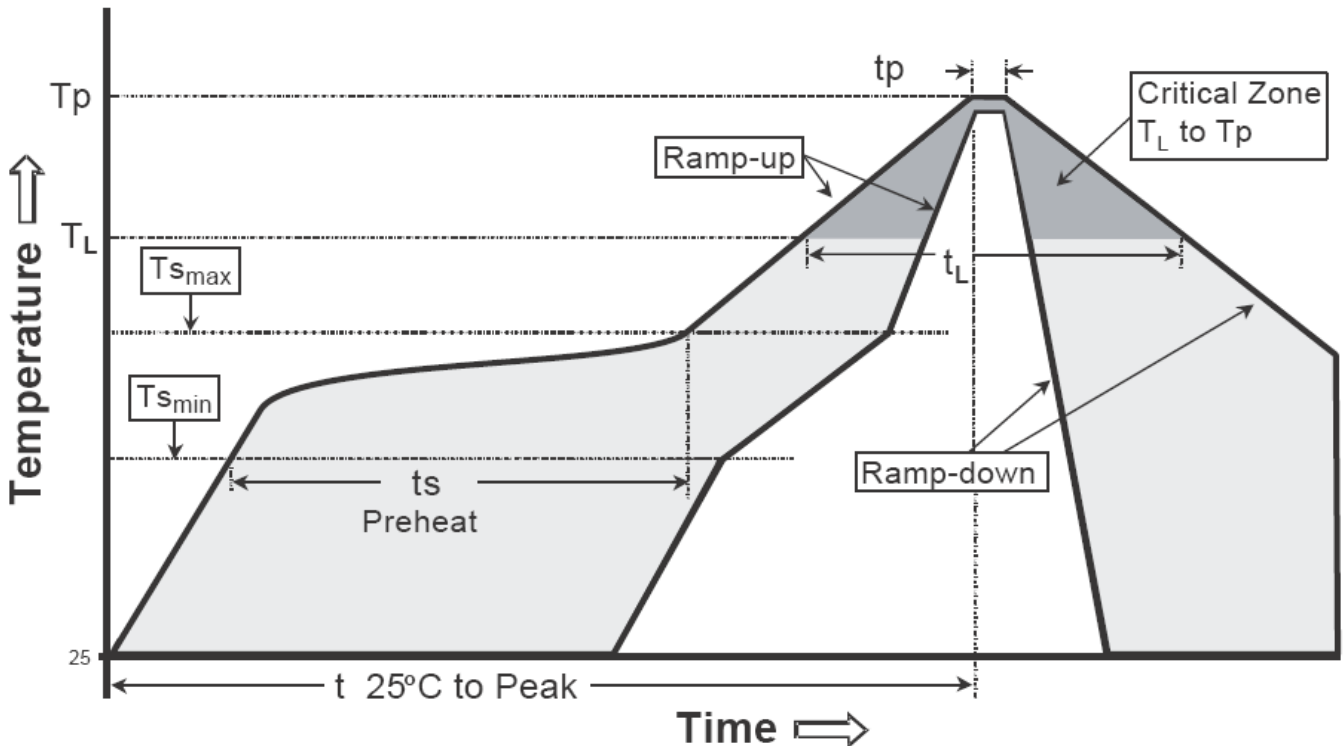
**Carrier Tape Dimension**



**Recommended wave soldering condition**

Product	Peak Temperature	Soldering Time
Pb-free devices	260 +0/-5 °C	5 +1/-1 seconds

**Recommended temperature profile for IR reflow**



Profile feature	Sn-Pb eutectic Assembly	Pb-free Assembly
Average ramp-up rate (T <sub>smax</sub> to T <sub>p</sub> )	3°C/second max.	3°C/second max.
Preheat		
-Temperature Min(T <sub>s min</sub> )	100°C	150°C
-Temperature Max(T <sub>s max</sub> )	150°C	200°C
-Time(t <sub>s min</sub> to t <sub>s max</sub> )	60-120 seconds	60-180 seconds
Time maintained above:		
-Temperature (T <sub>L</sub> )	183°C	217°C
- Time (t <sub>L</sub> )	60-150 seconds	60-150 seconds
Peak Temperature(T <sub>p</sub> )	240 +0/-5 °C	260 +0/-5 °C
Time within 5°C of actual peak temperature(t <sub>p</sub> )	10-30 seconds	20-40 seconds
Ramp down rate	6°C/second max.	6°C/second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.

Note : All temperatures refer to topside of the package, measured on the package body surface.



